Indian Streams Research Journal

International Recognized Multidisciplinary Research Journal

ISSN: 2230-7850

Impact Factor : 4.1625(UIF)

Volume -8 | Issue - 2 | March - 2016



GROWTH AND CHARACTERIZATION OF SULFANILAMIDE DOPED DIHYDROGEN HEXAFLUOROSILICATECRYSTAL





N. Mala¹, C. Muthuselvi², B. Ravikumar³ and S. Pandiarajan⁴ ^{1,2,3,4}Department of Physics, Devanga Arts College, Aruppukottai, Tamilnadu, India.

ABSTRACT :

Single crystals of sulfanilamide doped dihydrogen hexafluorosilicate were grown by slow evaporation method at the room temperature. The grown crystals are characterized by the powder XRD, FT-IR, FT-Raman, UV-Visible spectroscopy and SEM studies. The powder XRD, FT–IR and FT–Raman studies reveal the presence of dihydrogen hexafluorosilicate with the drug compound of sulfanilamide in the complex form. The optical properties of the title compound were analyzed by using the UV-Visible spectroscopy. The surface morphology of the complex crystal was analyzed from the SEM microphotograph.

KEYWORDS: Sulfanilamide-dihydrogen hexafluorosilicate; slow evaporation method; powder XRD; FT-IR; FT-Raman; UV-Visible spectroscopy; SEM

INTRODUCATION:

The antibacterial drug of sulfonamide is also called assulfanilamide. The chemical compound of sulfanilamide consists of aniline derivative with a sulfonamide group [1] .This medicinal important drug of sulfanilamide moiety comprises several types of pharmacological agents possessing antibacterial, antiviral, anti-carbonic anhydrase, diuretic and anticancer activities among the others [2-4]. It is also used in the treatment of vaginal yeast infections [5]. Many thousands of molecules containing the sulfanilamide structure have been created since its discovery yielding improved formulations with greater effectiveness and less toxicity [6]. In the present work, the sulfanilamide complex crystals with hydrofluoric acid were grown by the slow evaporation method at room temperature. Then the grown crystals were investigated by various techniques such as powder XRD, FT-IR, FT-Raman, UV-visible spectroscopy and SEM and their results are summarized in this present work.

2. MATERIALS AND METHODS

Materials

The raw materials used for this crystallization (sulfanilamide, hydrofluoric acid, double distilled water, ethanol) were purchased from the Merck, Mumbai, India with AR grade. Methods

This is the simplest way to grow the highly transparent crystals at room temperature. In this method, 10 ml aqueous solution of ethanol is taken in a 100 ml beaker. The sulfanilamide drug compound dissolve in aqueous solution of ethanol until get a saturated solution. Then hydrofluoric acid is made to dissolve in water and they are mixed well in the magnetic stirrer for 1 hour. The highly dissolved solution is filtered by whatman filter paper and poured in a petridish. The petridish is covered with a plastic with a few small holes for evaporation of solvents. The apparatus is placed undisturbed till the sufficient size of crystals is obtained in the petridish. The hydrofluoric acid reacts naturally with walls of the glass petridish [7]. The chemical reaction of HF acid with glass is given as follows

$$SiO_2 + 6 HF \rightarrow H_2SiF_6 + 2 H_2O$$

This H₂SiF₆ leads to the formation of the sulfanilamide doped complex crystals. Now the crystals are harvested. The photographic view of harvested crystal is shown in figure 1.



Fig.1: Photographic view of sulfanilamide doped dihydrogen hexafluorosilicate crystal

3. RESULTS AND DISCUSSIONS

3.1. Density measurement

The density of the grown crystal was determined using the flotation method by using the following relation,

$$\rho = \frac{(W_3 - W_1)}{W_2 - W_1}$$

ρ -Density of the crystal

W₁-Weight of empty specific gravity bottle

W₂- Weight of the specific gravity bottle with pure water

W₃- Weight of specific gravity bottle with solution

The density values of the parent and the complex crystals are tabulated in Table 1.

Compound Name	Density (g/cm ³)
Sulfanilamide	1.51
Dihydrogen hexafluorosilicate	1.22
Sulfanilamide complex	1.62

Table 1: Density values of parent and complex crystals

The density value of the complex crystal is entirely different from that of the pure parent crystal which confirms presence of the dihydrogen hexafluorosilicate (H_2SiF_6) in the sulfanilamide with the complex form.

3.2. Characterization

The sulfanilamide doped dihydrogen hexafluorosilicate crystal was analyzed by the powder XRD, FT–IR, FT–Raman, UV–Visible spectroscopy and SEM studies. The powder X–ray diffraction of the crystalline sample was carried out, using XPERT–PRO X–ray diffractometer with Cu K α (λ = 1.54060 Å) radiation. The FT-IR spectrum of the sample was recorded by using SHIMADZU FT-IR spectrometer in the range 4000–400 cm⁻¹. The sample for this measurement was finally ground and mixed with KBr. The mixture was pressed under vacuum at very high pressure to obtain a transparent disc, which yield good spectra. The FT-Raman spectrum of pure sulfanilamide and sulfanilamide doped hydrofluoric acid crystalswere recorded over the range 4000 – 80 cm⁻1with a resolution of 2 cm⁻¹ using the BRUKER RFS 27 FT-Raman spectrometer. The source used in this device was the Nd : YAG laser operated at 1064 nm with the incident power of 100 mW for excitation. The optical transmittance and absorbance spectrum of grown crystals have been recorded with SHIMADZU-UV1800, double beam spectrometer. Transmittance and absorbance data were observed for sulfanilamide doped dihydrogen hexafluorosilicate in the wavelength range 200–1100 nm insteps of 1nm. The slit width chosen was 1 nm. The wavelength rate was in medium mode. The observed values of absorbance were recorded and stored in the memory of a computer and plotted.

3. 3. Powder XRD Analysis

The X-ray diffraction spectra were recorded for sulfanilamide complex crystal is shown in figure 2. The 2θ and d-spacing values of the title compound is tabulated in Table 2.



Figure 2: Powder XRD diffraction pattern of sulfanilamide doped dihydrogen hexafluorosilicate crystal

Pos. [°2Th.]	Height [cts]	FWHM [°2Th.]	d-spacing [Å]	Rel. Int. [%]
10.8431	91.44	0.2007	8.15955	24.40
14.7574	171.31	0.4015	6.00291	45.71
18.0581	229.79	0.1171	4.91246	61.32
18.3116	300.08	0.1673	4.84502	80.07
19.0151	191.17	0.1338	4.66732	51.01
19.6175	188.79	0.1338	4.52533	50.38
20.8482	176.86	0.1338	4.26091	47.19
21.7094	270.36	0.1338	4.09378	72.14
22.4509	145.30	0.1338	3.96023	38.77
23.0556	374.76	0.1338	3.85771	100.00
26.1100	73.65	0.3346	3.41295	19.65
27.1110	104.67	0.3346	3.28916	27.93
28.7586	353.95	0.1338	3.10436	94.45
30.5217	122.76	0.2676	2.92894	32.76
31.7988	59.94	0.3346	2.81416	15.99
33.3584	71.79	0.4015	2.68607	19.16
35.2715	62.86	0.2676	2.54464	16.77
36.2944	33.29	0.3346	2.47524	8.88
42.1159	66.69	0.2676	2.14559	17.80
48.3533	37.76	0.6528	1.88084	10.08

Table 2: Powder XRD data of sulfanilamide doped dihydrogen hexafluorosilicate crystal

The X-ray diffraction patterns confirms that the formation of sulfanilamide complex in a crystalline behavior. The Debye–Scherrer formula relates the size of the crystallites in a solid to the broadening of a peak in a diffraction pattern equation in X-ray diffraction and crystallography.

The Debye–Scherrer equation is

$$D = \frac{0.94 \,\lambda}{\beta \cos \theta}$$

Where,

D = crystallite size, λ = wavelength of X-ray radiation (Cu Kα = 1.54060 Å) ϑ = diffraction angle

 β = Full width at half maximum height.

The crystallite size of the complex crystal of sulfanilamide is found to be 63.3 nm. The molecular structure of sulfanilamide complex with dihydrogen hexafluorosilicate crystal is depicted in figure 3.



Fig.3: Molecular structure of sulfanilamide doped dihydrogen hexafluorosilicate crystal

3.4. FT-IR and FT-Raman Spectroscopy Analyzes

The sulfanilamide doped molecule containing $-NH_2$ (sulfonamide), $-NH_2$ (aniline), $-SO_2$, -CH, -C-N, -C-C, Si-F and disubstituted benzene ring functional groups (fig. 3). The experimental FT–IR and FT–Ramanspectra of sulfanilamide complex crystal are shown in figure 4 and figure 5 respectively. The detailed wavenumber assignment in FT–IR and FT–Ramanspectra sulfanilamide complex crystals are given in Table 3.

3.4.1. Vibrations of -NH₂ (sulfonamide and aniline) groups

The NH₂ stretching modes of sulfanilamide in the region of IR spectrum is exhibiting around 3390–3230 cm⁻¹ and NH₂ bending , wagging frequencies are observed at 1629, 683 cm⁻¹ in the IR spectra[8]. In the present study, the bands are identified at 3360, 3374 cm⁻¹ and 3271 and 3264 cm⁻¹ in the FT-IR and Raman spectra for the NH₂ symmetric stretching modes of aniline and sulfonamide group of title compound respectively. The corresponding antisymmetric stretching modes do not appear in the both spectra of the title compound due to effect of hydrogen bonding network between the two molecules.



Figure 4: FT–IRspectrum of sulfanilamide doped dihydrogen hexafluorosilicate crystal

The bands corresponding to the NH₂ scissoring and wagging vibrations belong to the aniline ring group are expected near 1650 and 683 cm⁻¹ respectively [9]. The bending vibration occurs at 1580–1550 cm⁻¹ for sulfonamide group [8].In the IR and Raman spectra of sulfanilamide complex, the bands occur at 1630, 1629 cm⁻¹ respectively is assigned to the NH₂ scissoring mode of aniline. The wagging vibrations of the same group is exactly identified at 685 cm⁻¹ in both spectra of the title compound. Also band at 1555 cm⁻¹ in the IR spectrum is attributed to the NH₂ bending mode of sulfonamide group.

3.4.2. SO₂ group vibration

Normally, the antisymmetric and symmetric stretching modes of SO₂ group appear in the region 1360–1310 and 1165–1135 cm⁻¹ respectively [10]. In the present study, the observed bands at 1312, 1302 cm⁻¹ and 1150 cm⁻¹ in the both spectra were assigned to the v_{asym} (SO₂) and v_{sym} (SO₂) modes respectively and the corresponding bands observed closely in the Raman spectrum for these modes. The scissoring and wagging vibration of SO₂ group occurs nearly at 570, 520 cm⁻¹ respectively [8]. As seen from the IR and Raman spectrum, these modes are observed at 563, 516 cm⁻¹ for the title compound.



Figure 5: FT–Ramanspectrum of sulfanilamide doped dihydrogen hexafluorosilicate crystal

3.4.3. C–S & C–N group vibrations

The C–S stretching mode occurs at 636 cm⁻¹ and 625 cm⁻¹ in the infrared and Raman spectra respectively [11].In the present investigations it is observed by the medium intensity peak at 634 cm⁻¹ in the FT–Raman spectrum due to v_{CS} vibration. The C–N stretching vibration is observed at 1319 and 1318 cm⁻¹ in the IR and Raman spectra [11]. The same vibration is observed at 1312 and 1313 cm⁻¹ along with C–H deformation mode in both spectra respectively in the present work. The decrease in wavenumber values are attributed to weakening of C–N bond due to involvement of N atom in the hydrogen bonding network.

FT-IR Ū (cm ⁻¹) FT-Raman Ū (cm ⁻¹)		Assignments
3360 (s, br)	3374 (m)	v_{s} (NH ₂) _{aniline}
3271 (s, br)	3264 (w)	v_{s} (NH ₂) _{sulfonamide}
-	3068 (m)	v (C-H)
-	3052 (m)	v (C-H)
2675 (m)	-	
2362 (m)	-	
2015 (w)	-	
1917 (w)	-	Overtone and combination bands
1844 (w)	-	
1784 (w)	-	
1630 (m)	1629 (m)	δ_{s} (NH ₂) _{aniline} ; v (C-C)
1593 (m) 」	1563 (s)	v (C-C)
1555 (m)	-	δ (NH ₂) sulfonamide
1434 (m)	-	v (C=C)
1312 (m)	1313 (w)	v _{as} (SO ₂); β (C-H); ν (C-N)
1150 (s)	1156 (m)	ν _s (SO ₂); β (C-H)
1094 (m)	1091 (s)	β (C-H)

Table 3: FT-IR and FT-Raman wavenumber assignments for sulfanilamide doped dihydrogen				
hexafluorosilicate crystal				

GROWTH AND CHARACTERIZATION OF SULFANILAMIDE DOPED DIHYDROGEN

1003 (w)	1005 (w)	β (C-H)
968 (w)	966 (w)	ү (С-Н)
899 (s)	899 (m)	ү (С-Н)
831 (s)	841 (m)	γ (C-H); Ring breathing
-	820 (m)	γ (C-H)
-	715 (w)	v (Si-F)
685 (s, br)	685 (m)	ω (NH ₂) _{aniline} ; v (Si-F)
-	634 (m)	v (C-S)
542 (w)	539 (w)	β (Si-F ₂)
-	450 (w)	γ (Si-F ₂)

w-weak; s- very strong; m- medium; υ - stretching; υ s- sym. stretching

 v_{as} - asym. stretching; γ- out-of-plane bending; β- in-plane bending; δ- bending; ω- wagging; δs- scissoring

3.4.4. Disubstituted benzene ring vibrations

The C-H stretching modes of the disubstituted benzene ring are normally occurs in the region 3115–3005 cm⁻¹and this is the characteristic region for the identification of the C–H stretching vibrations. Also, the bands are not affected appreciably by the nature of the substituents in this region [12]. In the present study, the FT– Raman bands at 3068 and 3052 cm⁻¹respectively have been assigned to C-H stretching vibration and the expected C-H stretching vibrations do not appear in the FT-IR spectrum due to the hydrogen bonding effect. For 1,4 light heavy distributed benzenes, the in-plane bending vibrations of C-H are seen in the range 1315 -1225 cm⁻¹ and 1190 - 995 cm⁻¹ [13]. The title compound shows the peaks at 1312, 1150, 1094, 1003 cm⁻¹ and at 1313, 1156, 1091, 1005 cm⁻¹ in the infrared and Raman spectra respectively for this mode. The out-ofplane C–H deformation bands γ (C–H) are expected in the range 990 – 790 cm⁻¹ [13, 14]. As seen from the Table 3, the experimentally observed values in FT-IR and FT-Raman spectra are 968, 899, 831cm⁻¹ and 966, 899, 841, 820 cm⁻¹ respectively for γ (C–H) mode. In the substituted benzenes, the vibrations mainly involve 'quadrant stretching' of the phenyl C-C bonds. There are two quadrantstretching components in substituted benzenes which are expected to appear in the regions 1620-1585 cm⁻¹ and 1590–1565 cm⁻¹ respectively [15]. In experimental spectra, the bands are identified at 1630 cm⁻¹, 1593 cm⁻¹ in IR spectrum and 1629, 1593 cm⁻¹ in Raman spectrum corresponds to these C–C vibrations. Also C=C modes are observed experimentally as medium bands at 1434 cm⁻¹ in FT-IR and there is no counterpart in the Raman spectra. The ring breathing mode is observed at 831 cm⁻¹ and 841 cm⁻¹ in FT–IR and FT-Raman spectra of title compound.

3.4.5. Dihydrogen hexafluorosilicate group vibrations

The most intense absorption bands in the range of 750–680 cm⁻¹ include the v (Si-F) vibration. The in-plane bending vibrations δ (SiF₂) were assigned to the band around 465 cm⁻¹ and out-of-plane vibrations δ (SiF₂) were registered as a shoulder around 420 cm⁻¹ [16, 17].In the present study, the bands at 715, 685 cm⁻¹ and at 714, 685 cm⁻¹ in IR and Raman spectra are attributed to the stretching mode of Si-F respectively. The in-plane bending vibrations of SiF₂ are identified at 542 and 539 cm⁻¹ in both spectra of the title compound. The bands at 450 cm⁻¹ in both spectra are observed at the out-of-plane bending vibrations of SiF₂. This wavenumber assignment confirms the presence of dihydrogen hexafluorosilicate compound in the sulfanilamide drug crystal and it is linked with sulfanilamide through the intermolecular hydrogen bonding. This hydrogen

bonding shifts the stretching and deformation modes of vibrations to lower and higher wavenumber sides respectively.

3.5. UV- Visible Spectroscopy Analysis

The absorption spectrum of sulfanilamide doped with dihydrogen hexafluorosilicate is shown in figure 6. The crystal shows a good transmittance in the visible region which enables it to be a good material for optoelectronic applications. Also it is known that, there will be no significant absorption in the entire range of visible light. A good optical transmittance from UV-Vis-NIR spectrum, it is clear that the grown crystals have 99% transparent in the visible region. The lower cut-off wavelength was observed at 300 nm. The spectrum further indicates that the crystal has wide optical window from 300 nm to 1100 nm. This makes the usefulness of this material for optoelectronic applications. This study reveals that the grown crystal is optically transparent throughout the entire visible range.



Fig. 6: Absorbance spectrum of sulfanilamide doped dihydrogen hexafluorosilicate crystal

The band gap of the crystal was estimated by using the following the relation [18].

$$E_g = \frac{1.243 \times 10^3}{\lambda_{max}}$$

The band gap values of sulfanilamide doped with dihydrogen hexafluorosilicate crystal was found to be as 4.14 eV. This large band gap indicates the title compound is a typical dielectric material.

3.6. SEM Analysis

The morphology of as grown sulfanilamide doped with dihydrogen hexafluorosilicate crystal was observed by SEM. The microphotograph of the sulfanilamide doped with dihydrogen hexafluorosilicate is shown in figure 7. The doped crystals have a more irregular structure, greater particle size and rougher surface morphology. The greater particle size of the

doped ones can be explained by the fact that minimum crystal defects have been formed, when the dopant ions occupy regular lattice sites inside and for on the surface of sulfanilamide compound.



Fig.7. SEM image of sulfanilamide doped dihydrogen hexafluorosilicate crystal

4. CONCULSIONS

The sulfanilamide doped dihydrogen hexafluorosilicate single crystals were grown successfully by using slow evaporation method. The powder XRD study reveals formation of complex crystal. The FT-IR and FT-Raman bands have been assigned for sulfanilamide doped with dihydrogen hexafluorosilicate. This study also confirms the presence of dihydrogen hexafluorosilicate in the drug compound of sulfanilamide. The downshifting of stretching frequencies together with the increase in the deformation frequencies confirms the existence of extensive intermolecular hydrogen bonds. The UV-Visible spectral studies show that the crystal has the maximum transparency through the entire visible region. The band gap value is found to be as 4.14 eV. This large band gap indicates the title compound is a typical dielectric material. The SEM study shows that the grown crystal has the rough surface and irregular shape morphology.

ACKNOWLEDGEMENT

The authors sincerely acknowledge their thanks to the Management and Principal of Devanga Arts College, Aruppukottai for their permission and encouragement during their research work. Also the authors extend their thanks to the University Grants Commission (UGC) for the financial support of this work in the form of a Minor Research Project (MRP).

REFERENCES

- 1. M. Madigan, J. Martinko, D. Stahl, D. Clark, *Brock Biology of Microorganisms (13th ed.)*, Pearson Education, (2012) 797.
- 2. R.E. Smith, M. Ashiya, Nat. Rev. Drug. Discov., 6 (2007) 597.
- 3. C.T. Supuran , A. Casini , A. Scozzafava, *Development of sulfonamide carbonicanhydrase inhibitors,* CRC Press; Boca Raton (FL),USA, (2004) 67.

A. Casini , A. Scozzafava, C.T. Supuran, Expert Opin. Ther. Patents 12 (2002) 1307.

4. C.C. Brackett, H. Singh, J.H. Block, *Pharmacotherapy*, 24 (2004) 856.

- 5. P. A. Ajibade, G.A. Kolawole, P. O'Brien, M. Helliwell, J. Raftery, *Inorg. Chim.Acta.* 359 (2006) 3111.
- 6. A.F. Hollemann, E. Wiberg, Hollemann-Wiberg, *Lehrbuch der AnorganischenChemie*, Vol. 102, 34 ed., Berlin; New York, (2007).
- 7. P.G. Roegers, A Guide to the Complete Interperation of Infrared Spectra of Organic Structures, Wiley, Canada, (1994).
- C. Topacli, A. Topacli, *Journal of Molecular Structure*, 644 (2003) 145.
 A. Topacli, B. Kesimli, *Spectrosc. Lett*.34 (2001) 513.
- 9. H. T. Varghese, C. Y. Panicker, D. Philip, Spectrochim. Acta A. 65 (2006) 155.
- 10. H. Tanak, K. Pawlus, M. K. Marchewka, A. Pietraszko, Spectrochim. Acta A: Molecular and Biomolecular Spectroscopy, 118 (2014) 82.
- 11. B. L. Silva, P. T. C. Freire, F. E. A. Melo, I. Guedes, M. A. AraujoSilve, J. Mendes Filho, A. J. D. Moreno, J. Braz, *J. Phy.* 28 (1998) 19.
- 12. K. Nakamoto, *Infrared and Raman Spectra of Inorganic and Coordination Compounds,* Wiley: New York, (1986).
- 13.G. Ogruc Ildiz, S. Akyuz , Vib. Spectrosc.58 (2012) 12.
- 14. Vladimir O. Gelmboldt, Eduard V. Ganin , Larisa V. Koroeva , Mark M. Botoshansky , Marina S. Fonari, *Journal of Fluorine Chemistry* 131 (2010) 719.
- 15. V.O. Gelmboldt, A.A. Ennan, Ed.V. Ganin, Yu.A. Simonov, M.S. Fonari, M.M. Botoshansky, J. Fluorine Chem. 125 (2004) 1951.
- 16. C. Muthuselvi, E. Archana, G. Ponlakshmi and S. Pandiarajan, *Der Chemica Sinica*,7 (2016) 47.



N. Mala

Department of Physics, Devanga Arts College, Aruppukottai, Tamilnadu, India.